



### • General Description

The ZMD68302N combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ .

### • Features

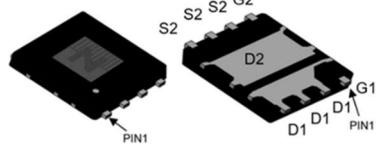
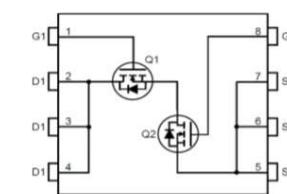
- Advance high cell density Trench technology
- Low  $R_{DS(ON)}$  to minimize conductive loss
- Low Gate Charge for fast switching
- Dual DIE in one package

### • Application

- DC/DC Converters in Computing
- Isolated DC/DC Converters in Telecom and Industrial

### • Product Summary

$V_{DS1} = 30V$
$V_{DS2} = 30V$
$R_{DS(ON)1} = 6.6m\Omega$
$R_{DS(ON)2} = 2.7m\Omega$
$I_{D1} = 55A$
$I_{D2} = 95A$



DFN5 x 6

### • Ordering Information:

Part NO.	ZMD68302N
Marking	ZMD68302
Packing Information	REEL TAPE
Basic ordering unit (pcs)	3000

### • Absolute Maximum Ratings ( $T_c = 25^\circ C$ ) (Q1)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_c = 25^\circ C$	55	A
	$I_D @ T_c = 75^\circ C$	41.8	A
	$I_D @ T_c = 100^\circ C$	34.7	A
Pulsed Drain Current <sup>(1)</sup>	$I_{DM}$	120	A
Total Power Dissipation( $T_c = 25^\circ C$ )	$P_D @ T_c = 25^\circ C$	60	W
Total Power Dissipation( $T_A = 25^\circ C$ )	$P_D @ T_A = 25^\circ C$	1.8	W
Operating Junction Temperature	$T_J$	-55 to 150	°C
Storage Temperature	$T_{STG}$	-55 to 150	°C
Single Pulse Avalanche Energy@ $L=0.1mH$	$E_{AS}$	45	mJ
Avalanche Current@ $L=0.1mH$	$I_{AS}$	30	A


**•Thermal resistance(Q1)**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	2.1	° C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	70	° C/W
Soldering temperature, wavesoldering for 10s	T <sub>sold</sub>	-	-	265	° C

**•Electronic Characteristics(Q1)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	30			V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.2		2.5	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V ,V <sub>DS</sub> =0V			±100	nA
Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =15A		6.6	8.5	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A		10	13	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =25V, I <sub>D</sub> =10A		12		s
Source-drain voltage	V <sub>SD</sub>	I <sub>S</sub> =15A			1.28	V

**•Electronic Characteristics(Q1)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V f = 1MHz	-	1150	-	pF
Output capacitance	C <sub>oss</sub>		-	175	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	136	-	

**•Gate Charge characteristics(T<sub>a</sub> = 25°C)(Q1)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Total gate charge	Q <sub>g</sub>	V <sub>DD</sub> = 15V I <sub>D</sub> = 15A V <sub>GS</sub> = 10V	-	18	-	nC
Gate - Source charge	Q <sub>gs</sub>		-	7	-	
Gate - Drain charge	Q <sub>gd</sub>		-	6	-	
Turn-ON Delay time	td(on)	V <sub>DD</sub> = 15V I <sub>D</sub> = 15A		4.5		ns
Turn-ON Rise time	tr			12		



Turn-Off Delay time	td(off)	$V_{GS} = 4.5V$ $R_{G,ext}=3.3\Omega$		26		
Turn-Off Fall time	tf			7.5		
Body Diode Reverse Recovery Time	trr	$IF=20A,$ $dI/dt=100A/\mu s$		6.5		ns
Body Diode Reverse Recovery Charge	Qrr			7		nC


**•Absolute Maximum Ratings (T<sub>c</sub> =25°C) (Q2)**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current	I <sub>D</sub> @TC=25°C	95	A
	I <sub>D</sub> @TC=75°C	72.2	A
	I <sub>D</sub> @TC=100°C	59.9	A
Pulsed Drain Current <sup>①</sup>	I <sub>DM</sub>	230	A
Total Power Dissipation(TC=25°C)	P <sub>D</sub> @TC=25°C	50	W
Total Power Dissipation(TA=25°C)	P <sub>D</sub> @TA=25°C	0.69	W
Operating Junction Temperature	T <sub>J</sub>	-55 to 150	°C
Storage Temperature	T <sub>STG</sub>	-55 to 150	°C
Single Pulse Avalanche Energy@L=0.1mH	E <sub>AS</sub>	180	mJ
Avalanche Current@L=0.1mH	I <sub>AS</sub>	60	A

**•Thermal resistance(Q2)**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	2.5	° C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	70	° C/W
Soldering temperature, wavesoldering for 10s	T <sub>sold</sub>	-	-	265	° C

**•Electronic Characteristics(Q2)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	30			V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.2		2.5	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V ,V <sub>DS</sub> =0V			±100	nA
Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A		2.7	3.6	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A		4.5	5.5	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =25V, I <sub>D</sub> =10A		18		s
Source-drain voltage	V <sub>SD</sub>	I <sub>S</sub> =20A			1.28	V


**•Electronic Characteristics(Q2)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	$C_{iss}$	V <sub>DS</sub> =25V f = 1MHz	-	2535	-	pF
Output capacitance	$C_{oss}$		-	196	-	
Reverse transfer capacitance	$C_{rss}$		-	139	-	

**•Gate Charge characteristics( $T_a = 25^\circ C$ )(Q2)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Total gate charge	$Q_g$	$V_{DD} = 15V$ $I_D = 20A$ $V_{GS} = 10V$	-	29	-	nC
Gate - Source charge	$Q_{gs}$		-	12	-	
Gate - Drain charge	$Q_{gd}$		-	11	-	
Turn-ON Delay time	$t_{d(on)}$	$V_{DD} = 15V$ $I_D = 20A$ $V_{GS} = 4.5V$ $R_{G,ext}=3.3\Omega$		18		ns
Turn-ON Rise time	$t_r$			9		
Turn-Off Delay time	$t_{d(off)}$			21		
Turn-Off Fall time	$t_f$			9		
Body Diode Reverse Recovery Time	$t_{rr}$	$IF=20A,$ $dI/dt=100A/\mu s$		18		ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			19		nC

Note: ① Pulse Test : Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$  ;



- Channel characteristics curve(Q1)

Fig.1 Gate-Charge Characteristics

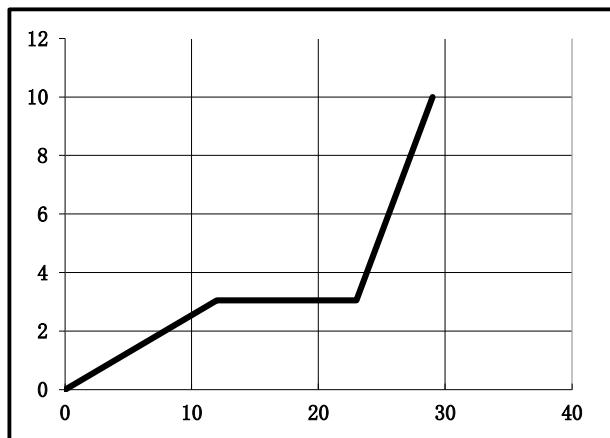


Fig.2 Capacitance Characteristics

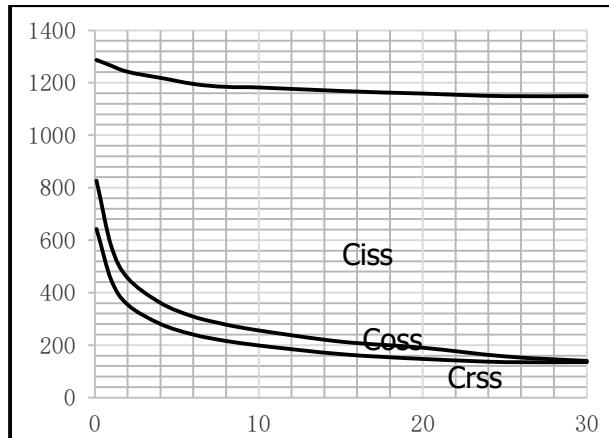


Fig.3 Power Dissipation

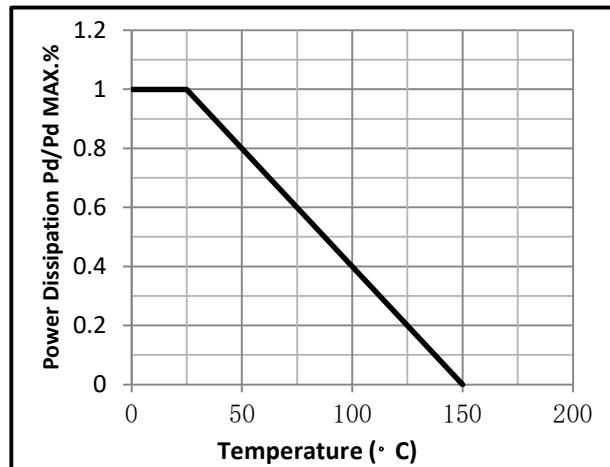


Fig.4 Typical output Characteristics

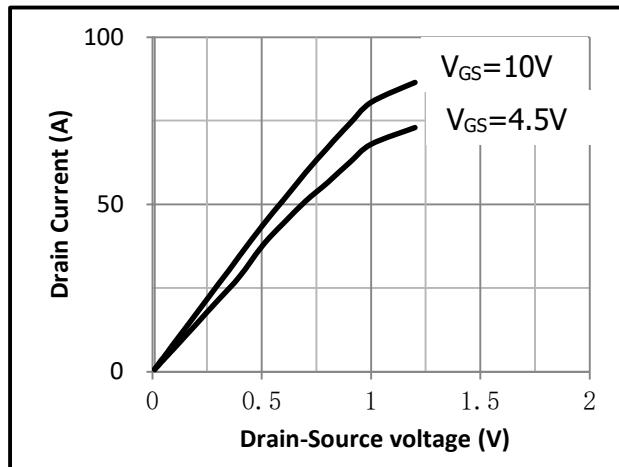


Fig.5 Threshold Voltage V.S Junction Temperature

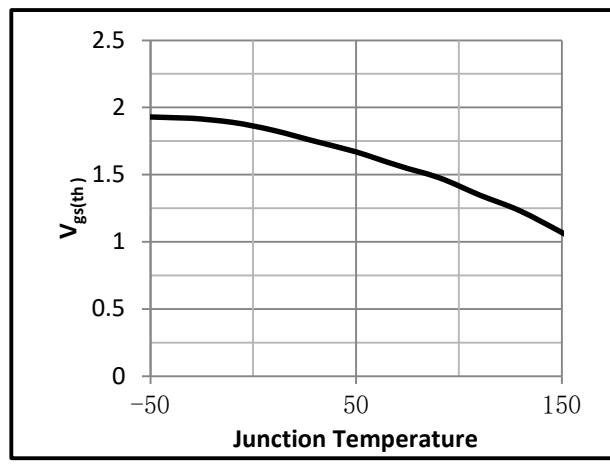


Fig.6 Resistance V.S Drain Current

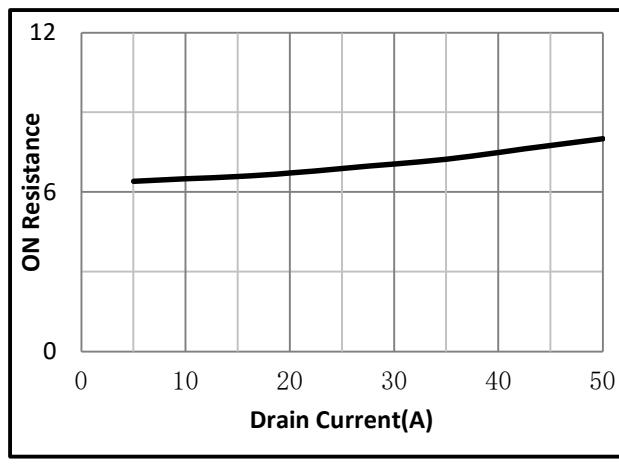




Fig.7 On-Resistance VS Gate Source Voltage

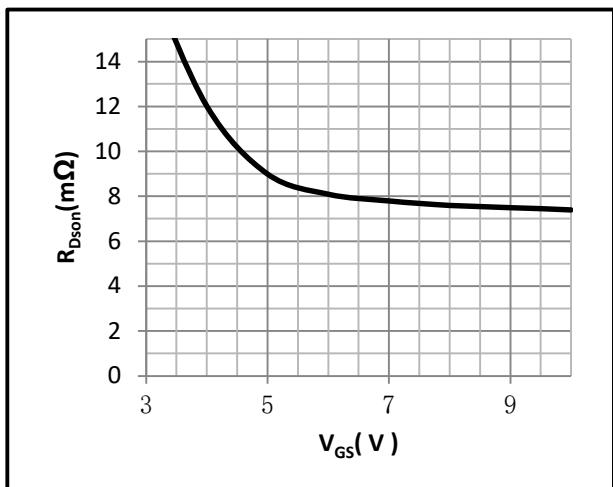


Fig.8 On-Resistance V.S Junction Temperature

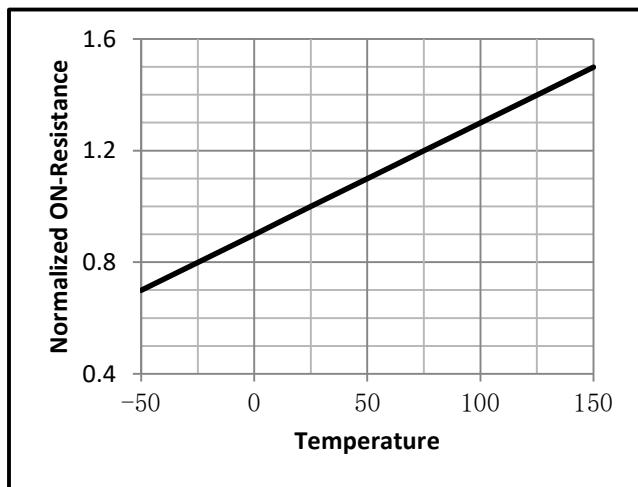
**• Channel characteristics curve(Q2)**

Fig.9 Gate-Charge Characteristics

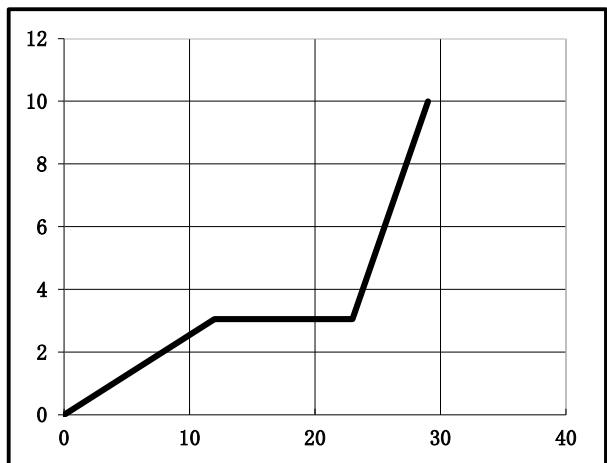


Fig.10 Capacitance Characteristics

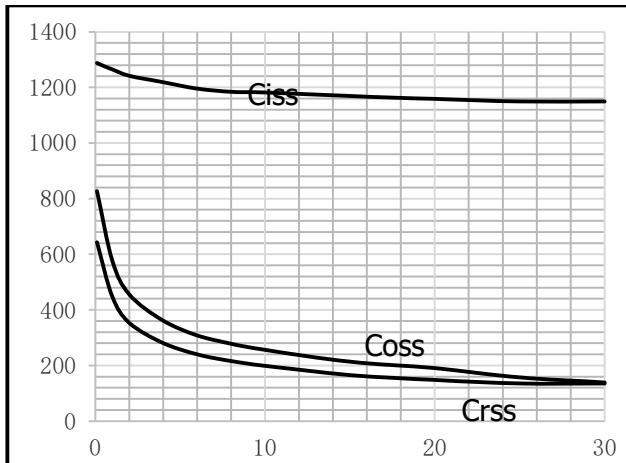


Fig.11 Power Dissipation

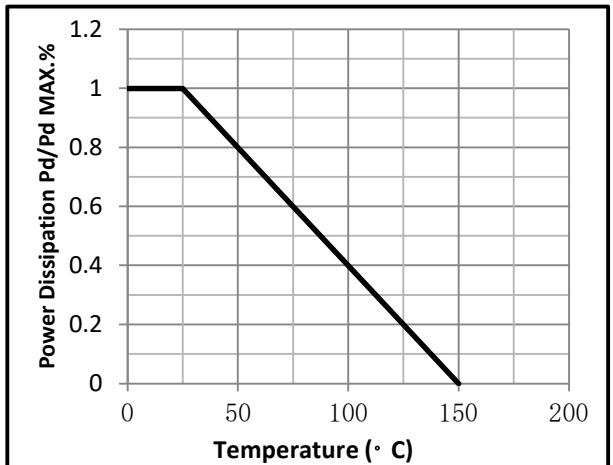


Fig.12 Typical output Characteristics

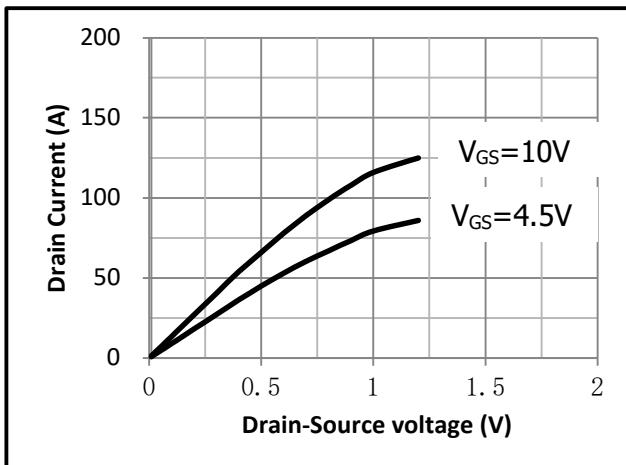




Fig.13 Threshold Voltage V.S Junction Temperature

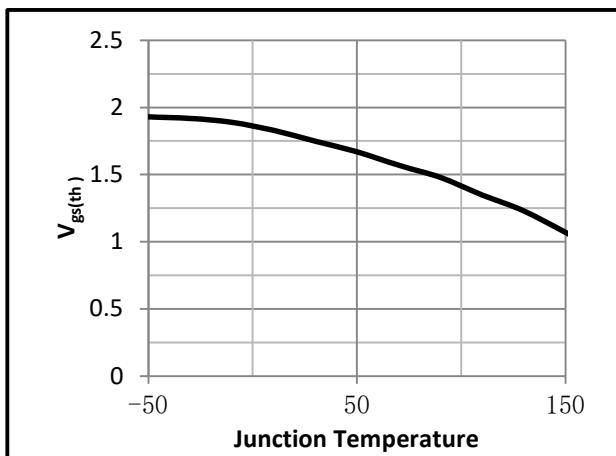


Fig.14 Resistance V.S Drain Current

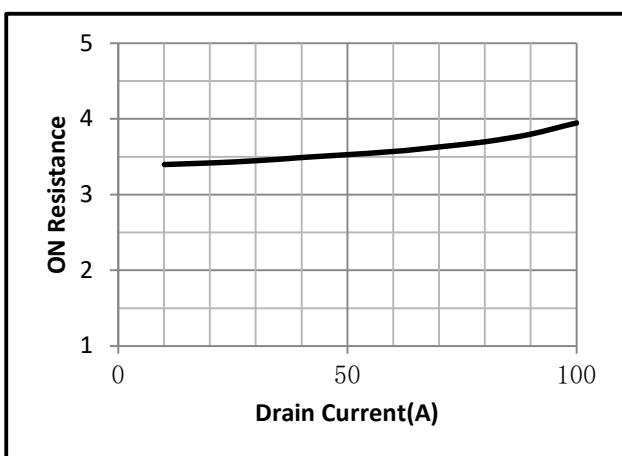


Fig.15 On-Resistance VS Gate Source Voltage

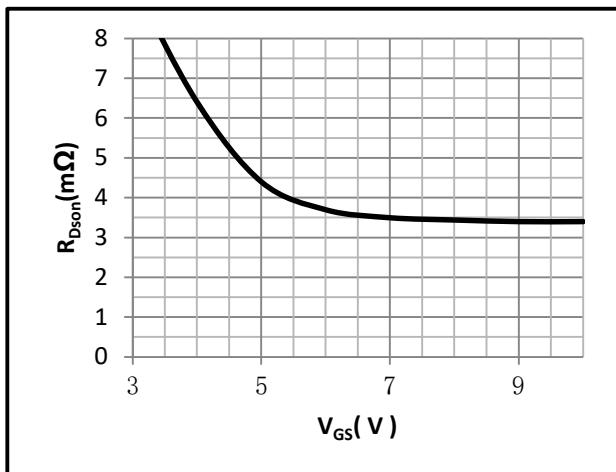


Fig.16 On-Resistance V.S Junction Temperature

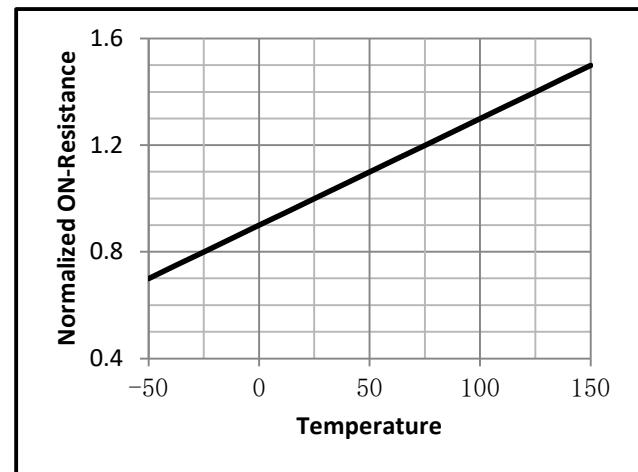




Fig.17 Gate Charge Measurement Circuit

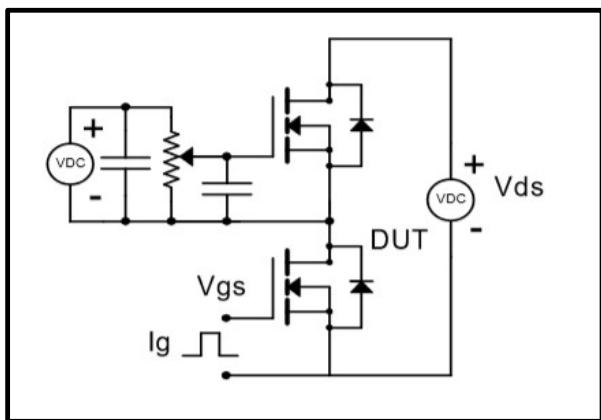


Fig.17 Gate Charge Waveform

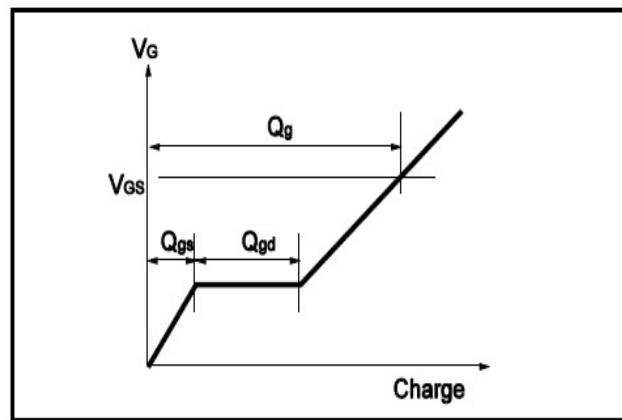


Fig.19 Switching Time Measurement Circuit

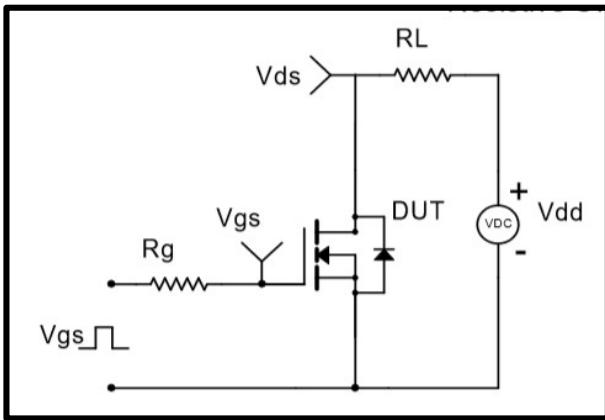


Fig.20 Switching Time Waveform

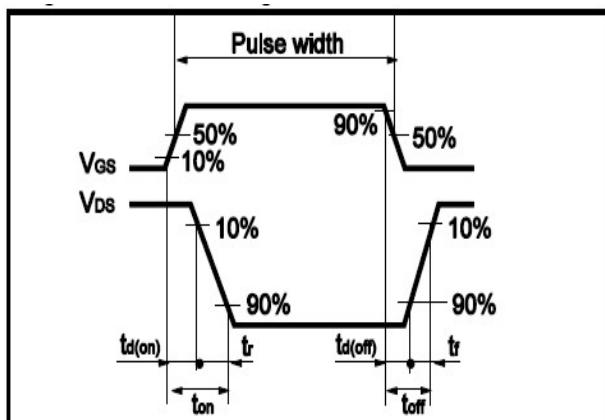


Fig.21 Avalanche Measurement Circuit

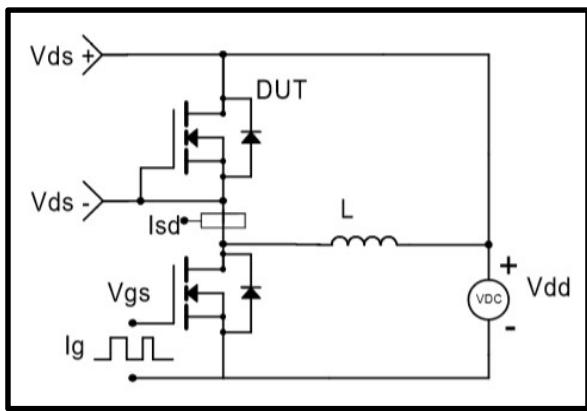
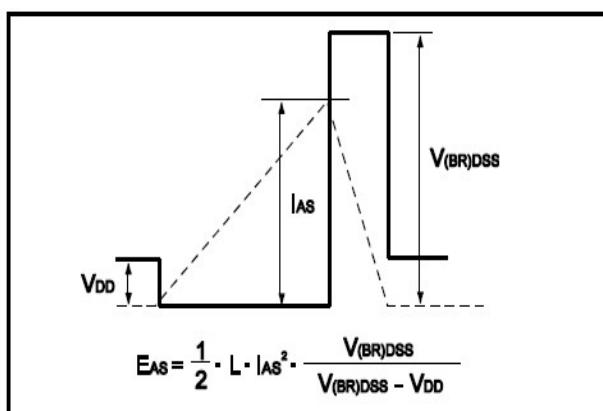


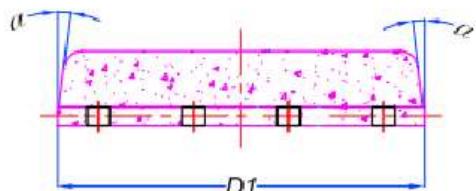
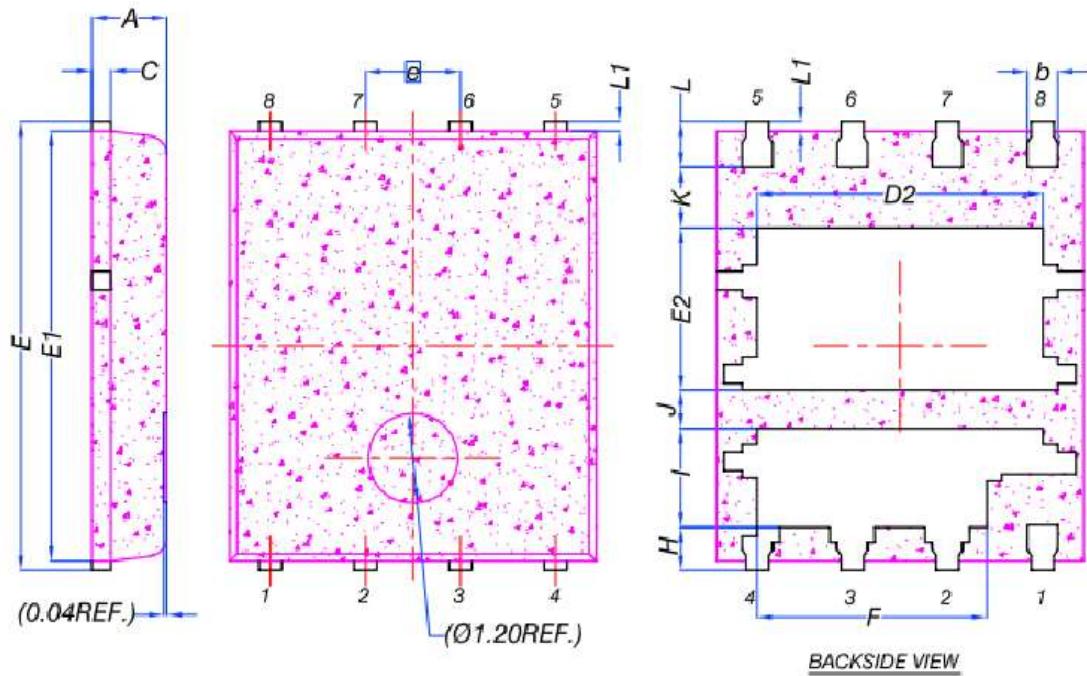
Fig.22 Avalanche Waveform





## •Dimensions (DFN5\*6)

Unit: mm



DIM.	MILLIMETERS		
	MIN.	NOM.	MAX.
A	0.90	1.00	1.10
b	0.33	0.41	0.51
C	0.20	0.25	0.30
D1	4.80	4.90	5.00
D2	3.61	3.81	3.96
E	5.90	6.00	6.10
E1	5.70	5.75	5.80
E2	2.02	2.17	2.32
e	1.27 BSC		
F	2.87	3.07	3.22
H	0.48	0.58	0.68
I	1.22	1.32	1.42
J	0.40	0.50	0.60
K	0.50	-	-
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
α	0°	-	12°